

Application/Control No.		Applicant(s)/Patent under Reexamination	
10/747	,620	HAN, JAE WON	
Exami	ner	Art Unit	
Kin-Ch	an Chen	1765	

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SEARCHED						
Class	Subclass	Date	Examiner			
205	87	9/6/05	kcc			
205	>91					
438	61-2					
	672					
	675					
	687					
	691					
	694					
	700					
	702					
438	703	9/6/05	ker			

INTERFERENCE SEARCHED						
Class	Subclass 672	Date 9/7/25-	Examiner			
	691					
438	7002	9/1/1-	kci			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Keywords search USPAT, USPG, Pub Epo Jpo, perwent 78 M. 708. Inventor search	8/30/5	kee		
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